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CONFIRMATION NO. 8779

SERIAL NUMBER 09/891,511	FILING DATE 06/27/2001 RULE	CLASS 438	GROUP ART UNIT 2812	ATTORNEY DOCKET NO. 010819	
APPLICANTS Mamoru Nakasuji, Kanagawa, JAPAN; Nobuharu Noji, Kanagawa, JAPAN; Tohru Satake, Kanagawa, JAPAN; Masahiro Hatakeyama, Kanagawa, JAPAN; Toshifumi Kimba, Kanagawa, JAPAN; Hirosi Sobukawa, Kanagawa, JAPAN; Shoji Yoshikawa, Tokyo, JAPAN; Takeshi Murakami, Tokyo, JAPAN; Kenji Watanabe, Kanagawa, JAPAN; Tsutomu Karimata, Kanagawa, JAPAN; Shin Oowada, Kanagawa, JAPAN; Mutsumi Saito, Kanagawa, JAPAN; Yuichiro Yamazaki, Tokyo, JAPAN; Takamitsu Nagai, Kanagawa, JAPAN; Ichirota Nagahama, Kanagawa, JAPAN;					
** CONTINUING DATA ***** <i>JB</i>					
** FOREIGN APPLICATIONS ***** <i>JB</i>					
JAPAN 2000-193104 06/27/2000 JAPAN 2000-229101 07/28/2000 JAPAN 2000-335934 11/02/2000 JAPAN 2001-11218 01/19/2001 <i>JB</i> JAPAN 2001-31901 02/08/2001 JAPAN 2001-31906 02/08/2001 JAPAN 2001-33599 02/09/2001 JAPAN 2001-35069 02/13/2001 JAPAN 2001-158662 05/28/2001 JAPAN 2001-162041 05/30/2001 JAPAN 2001-189304 06/22/2001					
IF REQUIRED, FOREIGN FILING LICENSE GRANTED ** 08/29/2001					
Foreign Priority claimed <input checked="" type="checkbox"/> yes <input type="checkbox"/> no 35 USC 119 (a-d) conditions <input checked="" type="checkbox"/> yes <input type="checkbox"/> no <input type="checkbox"/> Met after met Verified and Acknowledged <i>Jack Deerman</i> <i>JB</i> Examiner's Signature Initials		STATE OR COUNTRY JAPAN	SHEETS DRAWING 50	TOTAL CLAIMS 60	INDEPENDENT CLAIMS 13
ADDRESS 23850					
TITLE Inspection system by charged particle beam and method of manufacturing devices using the system <i>A. ees</i>					